## Application/Control No. Applicant(s)/Patent Under Reexamination 10/663,575 AGRAWAL ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2824 VanThu Nguyen **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 10-2003 365/230.08 US-6,631,094 B2 Ikeda, Hitoshi Α US-6,603,817 B1 08-2003 Hamamoto et al. 375/257 В US-С D US-US-E US-F US-G US-Н US-US-J

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